Interpretation of the \S-shaped" tem perature dependence of lum inescent peaks from sem iconductors

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The \S-shape" (decrease-increase-decrease) temperature dependence of luminescence peak shift from semiconductors is considered. A luminescence model for localized state ensemble was employed to interpret this anomalous temperature dependence of emission peak. Excellent agreement between the theoretical calculation and the experiments was achieved over the whole studied temperature region. The physical origin of the \S-shaped" shift is revealed.

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A nom alous tem perature dependence of lum inescence peak position has been frequently observed in sem iconductors. 1,2,3,4,5,6,7,8 A typical such phenom enon is so-called \S-shaped" tem perature dependence. That is, as the tem perature continuously increases, the lum inescence peak redshifts rst, then blueshifts, nally redshifts again. This unusual tem perature dependence of lum inescence peak signicantly deviates from that predicted by either the Varshnift or Bose-Einstein formula. For an ideally perfect sem iconductor, these formula predict a monotonic decrease of the sem iconductor band gap with increasing tem perature. The \S-shaped" tem perature-induced shift of lum inescence peak has been known to be closely related to the carrier localization in sem iconductors for a long time. Several attempts have been made to interpret the phenomenon. For example, a band-tail emission model was proposed by Eliseev et al. 2 to explain the frequently observed blueshift of the emission peak in InGaN QW s at higher temperatures. However, to our best knowledge, no a model can reproduce the \S-shaped" shift.

In this letter, starting from a newly developed luminescence model for localized state ensemble, 11,12 we quantitatively interpret the \S-shaped" temperature dependence of luminescence peaks from several representative materials. It is found that the redistribution of carriers within the localized states due to the transfer between dierent localized states and the thermal escape of carriers from the higher energy states leads to the occurrence of the \S-shaped" temperature dependence of the luminescence paek. Excellent agreement between the theoretical calculation and the experimental data is achieved over the whole studied temperature range.

Figure 1 shows the lum inescence peak positions against temperature for four dierent materials of InG aA sN, 3 G aInNP, 4 InG aN, 5 and A IG aN 6. The solid squares represent the experimental data while the solid lines are the calculated results using the model described in detail in ref. 12. The emission colors of these materials vary from ultraviolet (A IG aN, 3.9 eV) to near-infrared (InG aA sN, 0.965 eV). In these materials, the emission spectra are from the radiative recombination of the localized excitons due to either large-scale inhomogeneity in composition or the N-induced localized states. 3,4,5,6,13 Considering the radiative recombination, them all escape, and re-capture of the excitons in a localized state ensemble, we derive a distribution function of localized carriers from a rate equation under quasi-steady state. A ssum ing that the localized state ensemble has a Gaussian-type energetic distribution of density of states, the lum inescence spectrum of the localized excitons is found. The

tem perature dependence of the lum inescence peak positions can be given by 12

$$E(T) = E_0 \frac{T^2}{T + } \times (T) \ kT$$
: (1)

where the second term on the right describes the bandgap shrinking according to Varshni's empirical formula. is the Varshni's parameter and the Debye temperature. The third term represents the elect of thermal redistribution of localized carriers.  $k_{\rm s}$  is the Boltzmann constant. The dimensionless coel cient x (T) can be obtained by numerically solving the following equation  $^{11,12}$ 

$$xe^{x} = \frac{\pi}{k_B T} x \frac{\pi}{r} e^{(E_0 E_a) = k_B T};$$
 (2)

where  $E_0$  and are the central energy and broadening param eter for the distribution of the localized states, respectively.  $I=_{\rm tr}$  is the escape rate and  $I=_{\rm r}$  the radiative recombination rate of the localized carriers. Like the Ferm i level in the Ferm iD irac distribution function,  $E_a$  gives a special energy level below which the localized states are occupied by the excitons at 0 K. It is shown that the magnitude and sign of  $E_a$   $E_0$  strongly a lect the temperature dependence of the luminescence pack. When  $E_a$   $E_0$  is taken a negative value, the \S-shaped" temperature dependence (the solid lines) of the luminescence peak can be well produced, as shown in Fig. 1. The param eters adopted in the calculations are summarized in Table I.

As mentioned earlier,  $E_a$   $E_0$  plays an important role in determining the temperature behavior of the luminescence peak of the localized excitons, particularly in the low temperature region. As the central energetic position of the localized state distribution,  $E_0$  is determined for a given material. However, the energetic position of  $E_a$  is found to be dependent on both the concentration of carriers and the magnitude of the built-in electric eld in the material. The magnitude and even the sign of  $E_a$   $E_0$  can thus be changed through internally or externally adjusting the carrier density and the electric eld. Figure 2 shows the electrolum inescence peak positions (various symbols) as a function of temperature and injected current in InGaN single-quantum-well light-emitting-diode, reported by Eliseev at al. The solid curves are the calculated results using Eqs. (1) and (2). Excellent agreement between the theoretical results and the experimental data was obtained. The values of the parameters used in the calculations are also listed in Table I. From the table, an interesting observation is that the magnitude of  $E_a$   $E_0$  system atically varies with increasing

the injected electrical current during the measurements. It is known that the increase of the injected electric current can result in the increase of the carrier concentration. On the other hand, the increase of the injected electric current may cause a strength decrease of the electrical eld in the diode due to the screening out electrically injected carriers on the existing huge piezoelectric eld.  $^{14,15,16,17,18,19,20}$  Since the energetic position of E<sub>a</sub> is dependent on both the carrier concentration and the magnitude of the electric eld, it is not discuss for one to understand that the magnitude of E<sub>a</sub> E<sub>0</sub> changes with the injected electric current.

An interesting phenomenon in Fig. 2 is that the originally scattered electrolum inescence peaks in low temperature region for the dierent injected currents tend to converge at high temperatures. Figure 3(A) depicts the spectral peak positions of a blue InGaN single-quantum—well light—em itting—diode at several dierent temperatures as a function of the injected current. At 70 and 100 K, the peak position increases as the injected current increases. However, when the temperature 125 K, a plateau region appears. In other words, the peak position does not change with the injected current in the region. This indicates that at higher temperatures, the in uence of the magnitude of  $E_a$   $E_0$  on the temperature dependence of the peak positions will become weaker. This strange behavior can be well interpreted using Eqs. (1) and (2). At high temperatures, the solution of Eq. (2) can be found to be x  $(=k_BT)^2$  and Eq. (1) becomes  $e^{-11/12}$ 

$$E(T) = E_0 \frac{T^2}{T + \frac{2}{k_B T}}$$
: (3)

Note that  $E_a$   $E_0$  does not appear in the above equation, which indicates that the peak positions are no longer dependent on  $E_a$   $E_0$  at the high tem peratures. Figure 3(B) shows the calculated peak positions as a function of  $E_a$   $E_0$  for dierent tem peratures using Eqs. (1) and (2). Compared Fig. 3(A) with (B), it can be concluded that the behaviors in the experimental data is quantitatively produced by the theoretical calculations.

In conclusions, the \S-shaped" temperature dependence of the lum inescence peak positions, which is a frequently observed phenomenon in many semiconductors, is successfully modeled using a recently developed lum inescence model for localized state ensemble. The energetic dierence between the quasi-Fermilevel  $(E_a)$  and the central energy  $(E_0)$  of the localized state distribution essentially determines the details of temperature behavior of the luminescence peaks. The model could be useful for experimentalists to quantitatively

explain their experim ental results in temperature dependent lum inescence studies.

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## Figure Captions

- FIG. 1. The \S-shape" temperature dependence of lum inescence peak positions of several semiconductor materials. From the bottom to the top: GaInNAs (Ref. 3), GaInNP (Ref. 4), InGaN (Ref. 5) and AlGaN (Ref. 6). The scattered symbols are experimental data and the solid lines are the thing results using Eqs. 1) and (2).
- FIG. 2. Electrolum inescence peak positions (scattered symbols) of InGaN light-em ittingdiode under dierent injected currents as a function of temperature (from Ref.2). The solid lines are calculated results using Eqs. (1) and (2).
- FIG. 3. (A) Electrolum inescence peak positions of InG aN light-em itting-diode at several di erent tem peratures as a function of injected current (from Ref.21). (B) Calculated spectral peak positions for di erent tem peratures as a function of magnitude of  $E_a$   $E_0$ .

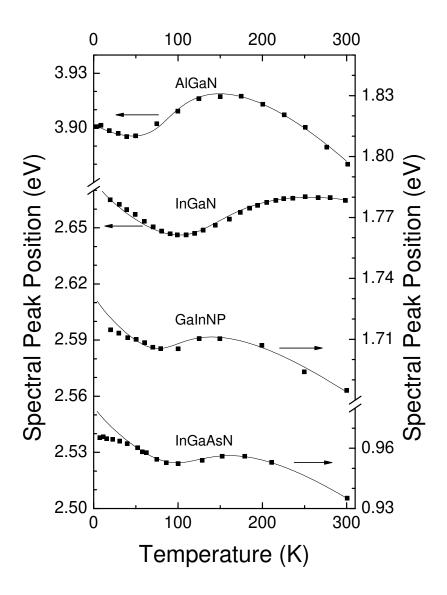


FIG.1: of 3.Q.Li, et al.

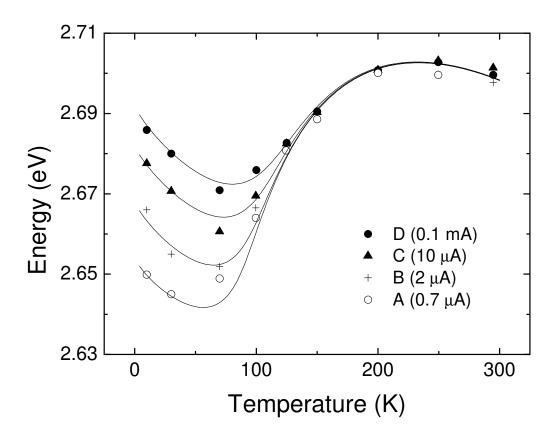


FIG.2: of 3.Q.Li, et al.

TABLE I: Param eters used to the temperature dependent energy peak positions in Figs. 1 and 2.

	E <sub>0</sub>		E <sub>a</sub> E <sub>0</sub>	tr= r		
	(eV)	(m eV)	(eV )		(m eV /K	) <b>(</b> K )
GaInNAs	1.025	25.0	-0.044	0.025	0.44	300
G aInN P	1.763	20.0	-0.031	0.01	0.42	300
InG aN	2.733	30 <b>.</b> 6	-0.057	0.018	0.35	700
A 1G aN	3.989	24.3	-0.086	0.2	0.94	700
А	2.78	31.5	-0.126	0.06	0.5	735
В	2.78	31.5	-0.112	0.04	0.5	735
С	2.78	31.5	-0.098	0.04	0.5	735
D	2.78	31.5	-0.88	0.04	0.5	735